Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/630,683	CHEN, YI-CHEN	
Examiner	Art Unit	
PHILIPPE S. DERAKSHANI	3754	

	SEARCHED		
Class	Subclass	Date	Examiner
248	447.1	2/1/2006	PD
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
248	447.1	2/1/2006	PD	

SEARCH (INCLUDING SEA	I NOTES RCH STRAT	EGY)
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